



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re DIVISIONAL Application of)
Shunpei YAMAZAKI)
Based On Serial No. 08:857,556) Art Unit: 2811
Which Was Filed: May 16, 1997) Examiner: S. Crane
For: METHOD OF FORMING INSULATING)
FILMS, CAPACITANCES, AND)
SEMICONDUCTOR DEVICES)Date: July 20, 2000

INFORMATION DISCLOSURE STATEMENT

Honorable Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, it is requested that the references listed on the attached Form PTO-1449 be made of record in the above-identified application.

The references listed on the attached Form PTO-1449 were cited in parent application Serial No. 08 857,556 filed May 16, 1997, and the predecessor

applications including Serial Nos. 08-250,344 filed May 27, 1994, and the predecessor applications including Serial No. 08-041,520, filed March 30, 1993; and Serial No. 07-729,533, filed July 5, 1991.

Respectfully submitted,

A handwritten signature in cursive script, appearing to read "Jeffrey L. Costellia", written over a horizontal line.

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Form PTO-1449
(Rev. 8-83)U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No. 0756-2183

Serial No. Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group: 2811

 JCN 177 U.S. PTO
 09/620368

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	4,849,081	7/18/89	Ross			
	3,607,679	9/1971	Melroy et al.			
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	Young et al., "Correlation... Ta ₂ O ₅ films", J. Fac. Sci. Technol., Vol. 14, No. 1, Jan/Feb 1977.
	Schrieber et al., J. Electrochem Soc., Vol. 123, No. 1, pp. 30-33 (1976)
	Suyama et al., "Electrical Conduction Mechanism and Breakdown Property in Sputter-Deposited Silicon Dioxide Films on Polycrystalline Silicon", J. Appl. Phys. Vol 65, No. 1, 1 January 1989, pp. 210-214
	Jones et al., "Effect of Oxygen on the rf-Sputtering Rate of SiO ₂ ", J. Vacuum Sci. and Technology, Vol. 5, No. 3, pp. 84-87.
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	Suyama et al., Chem. Abstracts 109573w, March 12, 1990, p. 750.

Examiner

Date Considered

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Croteau et al., "Growth and Characterisation of PD(Zr, Ti) ⁰³ Films Deposited by Reactive Sputtering of Metallic Targets" Proceedings of the Sixth IEEE International Symposium on Applications of Ferroelectrics, pp. 606-609, 1986.
	definition from Merriam Webster Collegiate Dictionary, Tenth Edition
	IEDM 11-14 Dec. 1988, pp. 222-225, San Francisco, Calif., U.S.; H. Takato et al.; "High Performance CMOS Surrounding Gate Transistor (SGT) for Ultra High Density LSIs".
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	Young et al., "Effect of Pulse Duration on the Annealing of Ion Implanted Silicon With a XeC1 Excimer Laser and Solar Cells", Mat. Res. Soc. Symp. Proc., Vol. 13, 1983, pp. 401-406.
	Schreiber et al., "High Quality RF-Sputtered Silicon Dioxide Layers", J. Electrochem. Soc., Vol. 123, No. 1, 1976, pp. 30-31.

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	5,136,534	8/1992	McDavid et al.			
	5,302,843	4/12/94	Yamazaki			
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	5,587,340	12/24/96	Yamazaki			
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	5,136,534	08/04/92	McDavid et al.			

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JP 01-171275	7/6/89	Japan			Abstract
JP 62-23117	1/31/87	Japan			Abstract
JP 62-298119	12/25/87	Japan			Abstract
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63-199456	8/17/88	Japan			X
1-248557	10/4/89	Japan			X
2-79475	3/20/90	Japan			X

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						Yes	No
	JP 59-99726	6/8/84	Japan			Abstract	
	JP 64-82557	03/28/89	Japan			Abstract	
	JP 01-225148	09/08/89	Japan			Abstract	
	JP 04-61337	02/27/92	Japan			Abstract	
	60-005555	01/12/85	Japan			Abstract	
	60-218472	11/01/85	Japan			Abstract	
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	63-096262	04/27/88	Japan			Abstract	
	1-218054	08/31/89	Japan			Abstract	

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